

1. Record Nr.	UNINA9910324456503321
Titolo	Fluid mechanics and measurements in two-phase flow systems : a symposium arranged by the Thermodynamics and Fluid Mechanics Group of the Institution of Mechanical Engineers and the Yorkshire Branch of the Institution of Chemical Engineers, 24-25 September 1969
Pubbl/distr/stampa	London : Institution of Mechanical Engineers, 1970
Descrizione fisica	VII, 251 p. : ill. ; 28 cm
Collana	Institution of Mechanical Engineers. Proceedings, 1969-70, v. 184, pt. 3C
Disciplina	620.1/06
Locazione	DINID
Collocazione	15 ID B/5-42
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di bibliografia	Includes bibliographical references.

2. Record Nr.	UNINA9910463409103321
Autore	Griffiths Bruce <1938->
Titolo	Competencies at work : providing a common language for talent management // Bruce Griffiths, Enrique Washington
Pubbl/distr/stampa	New York, NY : , : Business Expert Press, , 2015
Edizione	[First edition.]
Descrizione fisica	1 online resource (114 p.)
Collana	Human Resource Management and Organizational Behavior Collection
Disciplina	658.3125
Soggetti	Employees - Rating of Personnel management Competency-based education Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references (pages 83-88) and index.
Nota di contenuto	1. The underlying principles of competency modeling -- 2. A single competency examined -- 3. Competencies in the context of organizational systems -- 4. Universal competencies: the big six (plus one) -- 5. Case studies and examples -- Notes -- References -- Index.
Sommario/riassunto	Equips readers to understand, build, and implement competency models as a foundational and integrating element in talent management systems. Readers will understand how competency models have evolved to be the current best practice in defining criteria for all talent management applications such as selection interviews, promotion panels, assessment centers, job descriptions, and learning objectives. Specific guidance is provided in the steps needed to establish a sustainable model, with research results on universal competencies contained in most contemporary models. Also discussed are the challenges and issues in building and implementing models, such as the need for proof of efficiency and effectiveness, that is, reliable measures of competence and proof of validity. Competency models will be placed in the greater context of the complete talent management system needed to effectively recruit, select, orient, train, appraise, reward, motivate, and promote high-performing employees. The most popular competency applications of interviewing, assessment

centers, survey-guided development, job modeling, and training criteria are specifically explored and explained. Finally recent case studies bring competencies to life in real organizational settings. Questions for reflection will help readers review and summarize important content in each chapter.

3. Record Nr.	UNINA9910790955903321
Autore	Luger Peter <1943->
Titolo	Modern X-ray analysis on single crystals : a practical guide // Peter Luger
Pubbl/distr/stampa	Berlin, Germany : , : De Gruyter, , 2014 ©2014
ISBN	1-5231-0057-5 3-11-030828-2
Edizione	[Second fully revised and extended edition.]
Descrizione fisica	1 online resource (348 p.)
Classificazione	UQ 5600
Disciplina	548
Soggetti	X-ray crystallography
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Frontmatter -- Preface to the 1st edition -- Preface to the 2nd edition / Luger, Peter -- Contents -- 1. Introduction -- 2. Fundamental results of diffraction theory, X-radiation -- 3. Preliminary experiments -- 4. Crystal symmetry -- 5. Diffractometer measurements -- 6. Computer programs -- 7. Solution of the phase problem -- 8. Refinements -- 9. Structure analysis at non-routine conditions -- 10. Concluding remarks and outlook -- Appendix: Mathematics -- Bibliography -- Index
Sommario/riassunto	An excellent book for professional crystallographers! In 2012 the crystallographic community celebrated 100 years of X-ray diffraction in honour of the pioneering experiment in 1912 by Max von Laue, Friedrich and Knipping. Experimental developments e.g. brilliant X-ray sources, area detection, and developments in computer hardware and software have led to increasing applications in X-ray analysis. This completely revised edition is a guide for practical work in X-ray analysis. An introduction to basic crystallography moves quickly to a

practical and experimental treatment of structure analysis. Emphasis is placed on understanding results and avoiding pitfalls. Essential reading for researchers from the student to the professional level interested in understanding the structure of molecules.
